

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Hiroya FUKUYAMA, et al.
SERIAL NO. : (Unassigned)
FILED : (Herewith)
FOR : MICROSCOPIC OBSERVING APPARATUS AND
PROBE MICROSCOPE
GROUP ART UNIT : (Unassigned)
Examiner : (Unassigned)

COMMISSIONER FOR PATENTS
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Alexandria, Virginia 22313-1450

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97 & § 1.98**

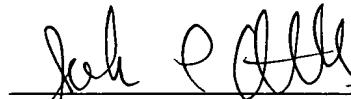
SIR:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

In accordance with the requirements of 37 C.F.R. § 1.98, copies of the references are submitted herewith.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,


John C. Altmiller
(Reg. No. 25,951)

Dated: 21 April 2004

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FORM PTO-1449**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)**

Atty Docket No. : 12706/13
 Serial No. :
 Inventors : Hiroya FUKUYAMA, et al.
 Filed :
 Group Art Unit :
 Examiner :

U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Patent Date</u>	<u>Name</u>	<u>Class/Subclass</u>	<u>Filing Date</u>
_____	_____	_____	_____	_____	_____
_____	_____	_____	_____	_____	_____
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_____	_____	_____	_____	_____	_____

FOREIGN PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>Class/Subclass</u>	<u>Translation Yes</u> <u>No</u>
_____	2002-272674	09/24/02	Japan	_____	X
_____	08-131455	05/28/96	Japan	_____	X
_____	62-134615	06/17/87	Japan	_____	X
_____	_____	_____	_____	_____	_____
_____	_____	_____	_____	_____	_____

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.